

# IEEE SCC20 25-1 Draft Meeting Agenda

**Draft 1 – January 29, 2025, M. Seavey**

**Dates:** June 3 through June 5, 2025  
(Tuesday, Wednesday, Thursday)

**Location:** DE&S Deca Sealand U.K.

Microsoft Teams Information for remote participation will be made available in a separate message.

*The order of the meetings and their times are subject to change to accommodate the availability of participants as necessary.*

## **Tuesday June 3:**

*All times will be listed in Coordinated Universal Time (UTC)*

<i>Time:</i>	<i>Meeting:</i>	<i>Room:</i>
TBD	<b>SCC20 Standards Committee Plenary Meeting</b>	TBD
TBD	<b>P1871.3 Working Group Meeting</b> Using JavaScript Object Notation (JSON) with XML-based Data Models	TBD
TBD	Lunch	
TBD	<b>Study Group Meeting</b> ATML-compatible representation in SysML of test requirements information for electronic systems.	TBD

## **Wednesday June 4:**

<i>Time:</i>	<i>Meeting:</i>	<i>Room:</i>
TBD	<b>Study Group Meeting (continued)</b> ATML-compatible representation in SysML of test requirements information for electronic systems.	TBD
TBD	<b>SIMICA Base Doc., MAI, and Test Results</b>	TBD
TBD	Lunch	
TBD	<b>P1671 Working Group Meeting</b> Automatic Test Markup Language (ATML)	TBD
TBD	<b>P2848 Working Group Meeting</b> Prognostics and Health Management in Automatic Test Systems	TBD

## **Thursday June 5:**

<i>Time:</i>	<i>Meeting:</i>	<i>Room:</i>
TBD	<b>P1671 Working Group Meeting (continued)</b> Automatic Test Markup Language (ATML)	TBD
TBD	Lunch	
TBD	<b>Executive Committee Meeting (E.g., Steering)</b>	TBD
TBD	<b>P1232 Working Group Meeting</b> Standard for System Diagnostic Data and Services (was AI-ESTATE)	TBD

*Address any PAR Extensions, New PARs, or PARs for Revisions to published Standards.*